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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	72MHz
Connectivity	I ² C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	21
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	1.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 13x14b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	24-SSOP (0.154", 3.90mm Width)
Supplier Device Package	24-QSOP
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8lb11f16e-b-qsop24r

I2C Slave (I2CSLAVE0)

The I2C Slave interface is a 2-wire, bidirectional serial bus that is compatible with the I2C Bus Specification 3.0. It is capable of transferring in high-speed mode (HS-mode) at speeds of up to 3.4 Mbps. Firmware can write to the I2C interface, and the I2C interface can autonomously control the serial transfer of data. The interface also supports clock stretching for cases where the core may be temporarily prohibited from transmitting a byte or processing a received byte during an I2C transaction. This module operates only as an I2C slave device.

The I2C module includes the following features:

- Standard (up to 100 kbps), Fast (400 kbps), Fast Plus (1 Mbps), and High-speed (3.4 Mbps) transfer speeds
- Support for slave mode only
- Clock low extending (clock stretching) to interface with faster masters
- Hardware support for 7-bit slave address recognition
- Transmit and receive FIFOs (two byte) to help increase throughput in faster applications
- Hardware support for multiple slave addresses with the option to save the matching address in the receive FIFO

16-bit CRC (CRC0)

The cyclic redundancy check (CRC) module performs a CRC using a 16-bit polynomial. CRC0 accepts a stream of 8-bit data and posts the 16-bit result to an internal register. In addition to using the CRC block for data manipulation, hardware can automatically CRC the flash contents of the device.

The CRC module is designed to provide hardware calculations for flash memory verification and communications protocols. The CRC module supports the standard CCITT-16 16-bit polynomial (0x1021), and includes the following features:

- Support for CCITT-16 polynomial
- Byte-level bit reversal
- Automatic CRC of flash contents on one or more 256-byte blocks
- Initial seed selection of 0x0000 or 0xFFFF

Configurable Logic Units (CLU0, CLU1, CLU2, and CLU3)

The Configurable Logic block consists of multiple Configurable Logic Units (CLUs). CLUs are flexible logic functions which may be used for a variety of digital functions, such as replacing system glue logic, aiding in the generation of special waveforms, or synchronizing system event triggers.

- Four configurable logic units (CLUs), with direct-pin and internal logic connections
- Each unit supports 256 different combinatorial logic functions (AND, OR, XOR, muxing, etc.) and includes a clocked flip-flop for synchronous operations
- Units may be operated synchronously or asynchronously
- May be cascaded together to perform more complicated logic functions
- Can operate in conjunction with serial peripherals such as UART and SPI or timing peripherals such as timers and PCA channels
- Can be used to synchronize and trigger multiple on-chip resources (ADC, DAC, Timers, etc.)
- Asynchronous output may be used to wake from low-power states

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Power Supply Rejection Ratio	PSRR _{ADC}	At 1 kHz	—	66	—	dB
		At 1 MHz	—	43	—	dB
DC Performance						
Integral Nonlinearity	INL	14 Bit Mode	-3.5 ⁴	-1.2 / +5	8.5 ⁴	LSB
		12 Bit Mode	-1.9	-0.35 / +1	1.9	LSB
		10 Bit Mode	-0.6	±0.2	0.6	LSB
Differential Nonlinearity (Guaranteed Monotonic)	DNL	14 Bit Mode	-1 ⁴	±1	2.5 ⁴	LSB
		12 Bit Mode	-0.9	±0.3	0.9	LSB
		10 Bit Mode	-0.5	±0.2	0.5	LSB
Offset Error ⁵	E _{OFF}	14 Bit Mode	-8 ⁴	-2.5	8 ⁴	LSB
		12 Bit Mode	-2	0	2	LSB
		10 Bit Mode	-1	0	1	LSB
Offset Temperature Coefficient	TC _{OFF}		—	0.011	—	LSB/°C
Slope Error	E _M	14 Bit Mode	-15 ⁴	—	15 ⁴	LSB
		12 Bit Mode	-2.6	—	2.6	LSB
		10 Bit Mode	-1.1	—	1.1	LSB
Dynamic Performance 10 kHz Sine Wave Input 1 dB below full scale, Max throughput, using AGND pin						
Signal-to-Noise	SNR	14 Bit Mode	66 ⁴	72	—	dB
		12 Bit Mode	64	68	—	dB
		10 Bit Mode	59	61	—	dB
Signal-to-Noise Plus Distortion	SNDR	14 Bit Mode	66 ⁴	72	—	dB
		12 Bit Mode	64	68	—	dB
		10 Bit Mode	59	61	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD	14 Bit Mode	—	-74	—	dB
		12 Bit Mode	—	-72	—	dB
		10 Bit Mode	—	-69	—	dB
Spurious-Free Dynamic Range	SFDR	14 Bit Mode	—	74	—	dB
		12 Bit Mode	—	74	—	dB
		10 Bit Mode	—	71	—	dB

Note:

1. This time is equivalent to four periods of a clock running at 18 MHz + 2%.
2. Conversion Time does not include Tracking Time. Total Conversion Time is:

$$\text{Total Conversion Time} = [\text{RPT} \times (\text{ADTK} + \text{NUMBITS} + 1) \times \text{T}(\text{SARCLK})] + (\text{T}(\text{ADCCLK}) \times 4)$$

where RPT is the number of conversions represented by the ADRPT field and ADCCLK is the clock selected for the ADC.
3. Absolute input pin voltage is limited by the V_{IO} supply.
4. Measured with characterization data and not production tested.
5. The offset is determined using curve fitting since the specification is measured using linear search where the intercept is always positive.

4.1.12 DACs

Table 4.12. DACs

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}		12			Bits
Throughput Rate	f_S		—	—	200	ksps
Integral Nonlinearity	INL	DAC0 and DAC2	-10	-1.77 / 1.56	10	LSB
		DAC1 and DAC3	-11.5	-2.73 / 1.11	11.5	LSB
Differential Nonlinearity	DNL		-1	—	1	LSB
Output Noise	$V_{\text{REF}} = 2.4 \text{ V}$ $f_S = 0.1 \text{ Hz to } 300 \text{ kHz}$		—	110	—	μV_{RMS}
Slew Rate	SLEW		—	± 1	—	V/ μs
Output Settling Time to 1% Full-scale	t_{SETTLE}	V_{OUT} change between 25% and 75% Full Scale	—	2.6	5	μs
Power-on Time	t_{PWR}		—	—	10	μs
Voltage Reference Range	V_{REF}		1.15	—	V_{DD}	V
Power Supply Rejection Ratio	PSRR	DC, $V_{\text{OUT}} = 50\%$ Full Scale	—	78	—	dB
Total Harmonic Distortion	THD	$V_{\text{OUT}} = 10 \text{ kHz}$ sine wave, 10% to 90%	54	—	—	dB
Offset Error	E_{OFF}	$V_{\text{REF}} = 2.4 \text{ V}$	-8	0	8	LSB
Full-Scale Error	E_{FS}	$V_{\text{REF}} = 2.4 \text{ V}$	-13	± 5	13	LSB
External Load Impedance	R_{LOAD}		2	—	—	k Ω
External Load Capacitance ¹	C_{LOAD}		—	—	100	pF
Load Regulation		$V_{\text{OUT}} = 50\%$ Full Scale $I_{\text{OUT}} = -2 \text{ to } 2 \text{ mA}$	—	100	1300	$\mu\text{V}/\text{mA}$

Note:

1. No minimum external load capacitance is required. However, under low loading conditions, it is possible for the DAC output to glitch during start-up. If smooth start-up is required, the minimum loading capacitance at the pin should be a minimum of 10 pF.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Negative Hysteresis Mode 3 (CPMD = 11)	HYS _{CP-}	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	-4	—	mV
		CPHYN = 10	—	-8	—	mV
		CPHYN = 11	—	-16	—	mV
Input Range (CP+ or CP-)	V _{IN}		-0.25	—	V _{IO} +0.25	V
Input Pin Capacitance	C _{CP}		—	7.5	—	pF
Internal Reference DAC Resolution	N _{bits}		6			bits
Common-Mode Rejection Ratio	CMRR _{CP}		—	70	—	dB
Power Supply Rejection Ratio	PSRR _{CP}		—	72	—	dB
Input Offset Voltage	V _{OFF}	T _A = 25 °C	-10	0	10	mV
Input Offset Tempco	TC _{OFF}		—	3.5	—	μV/°

4.1.14 Configurable Logic

Table 4.14. Configurable Logic

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Propagation Delay	t _{DLY}	Through single CLU Using an external pin	—	—	35.3	ns
		Through single CLU Using an internal connection	—	3	—	ns
Clocking Frequency	F _{CLK}	1 or 2 CLUs Cascaded	—	—	73.5	MHz
		3 or 4 CLUs Cascaded	—	—	36.75	MHz

4.1.15 Port I/O

Table 4.15. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output High Voltage (High Drive)	V_{OH}	$I_{OH} = -7 \text{ mA}$, $V_{IO} \geq 3.0 \text{ V}$	$V_{IO} - 0.7$	—	—	V
		$I_{OH} = -3.3 \text{ mA}$, $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	$V_{IO} \times 0.8$	—	—	V
		$I_{OH} = -1.8 \text{ mA}$, $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Output Low Voltage (High Drive)	V_{OL}	$I_{OL} = 13.5 \text{ mA}$, $V_{IO} \geq 3.0 \text{ V}$	—	—	0.6	V
		$I_{OL} = 7 \text{ mA}$, $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	—	—	$V_{IO} \times 0.2$	V
		$I_{OL} = 3.6 \text{ mA}$, $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Output High Voltage (Low Drive)	V_{OH}	$I_{OH} = -4.75 \text{ mA}$, $V_{IO} \geq 3.0 \text{ V}$	$V_{IO} - 0.7$	—	—	V
		$I_{OH} = -2.25 \text{ mA}$, $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	$V_{IO} \times 0.8$	—	—	V
		$I_{OH} = -1.2 \text{ mA}$, $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Output Low Voltage (Low Drive)	V_{OL}	$I_{OL} = 6.5 \text{ mA}$, $V_{IO} \geq 3.0 \text{ V}$	—	—	0.6	V
		$I_{OL} = 3.5 \text{ mA}$, $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	—	—	$V_{IO} \times 0.2$	V
		$I_{OL} = 1.8 \text{ mA}$, $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Input High Voltage	V_{IH}		$0.7 \times V_{IO}$	—	—	V
Input Low Voltage	V_{IL}		—	—	$0.3 \times V_{IO}$	V
Pin Capacitance	C_{IO}		—	7	—	pF
Weak Pull-Up Current ($V_{IN} = 0 \text{ V}$)	I_{PU}	$V_{DD} = 3.6$	-30	-20	-10	μA
Input Leakage (Pullups off or Analog)	I_{LK}	$\text{GND} < V_{IN} < V_{IO}$	-1.1	—	4	μA
Input Leakage Current with V_{IN} above V_{IO}	I_{LK}	$V_{IO} < V_{IN} < V_{IO} + 2.5 \text{ V}$ Any pin except P3.0, P3.1, P3.2, or P3.3	0	5	150	μA

5. Typical Connection Diagrams

5.1 Power

Figure 5.1 Power Connection Diagram on page 31 shows a typical connection diagram for the power pins of the device.

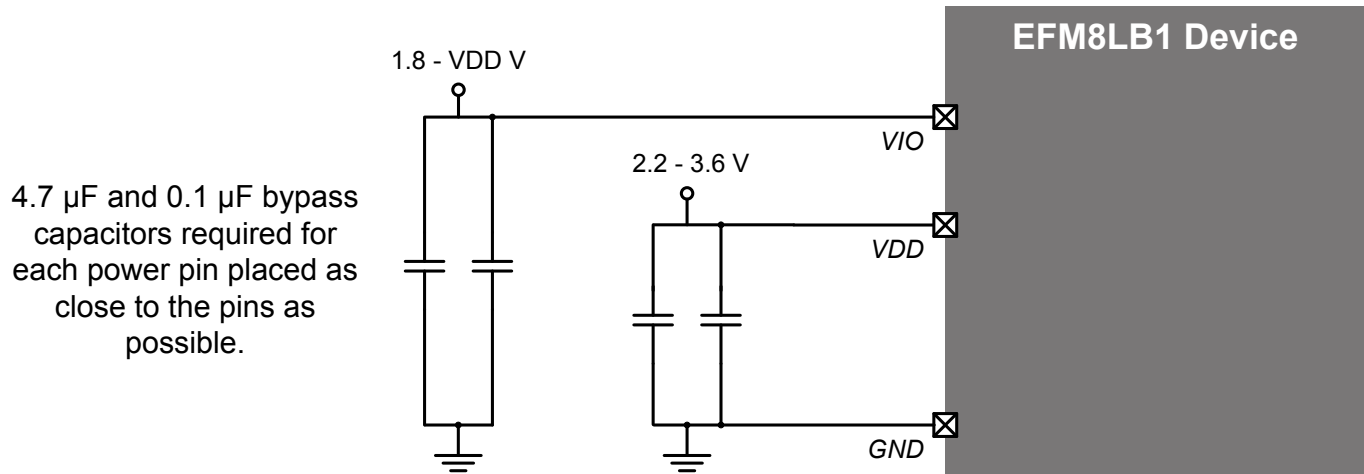


Figure 5.1. Power Connection Diagram

6. Pin Definitions

6.1 EFM8LB1x-QFN32 Pin Definitions

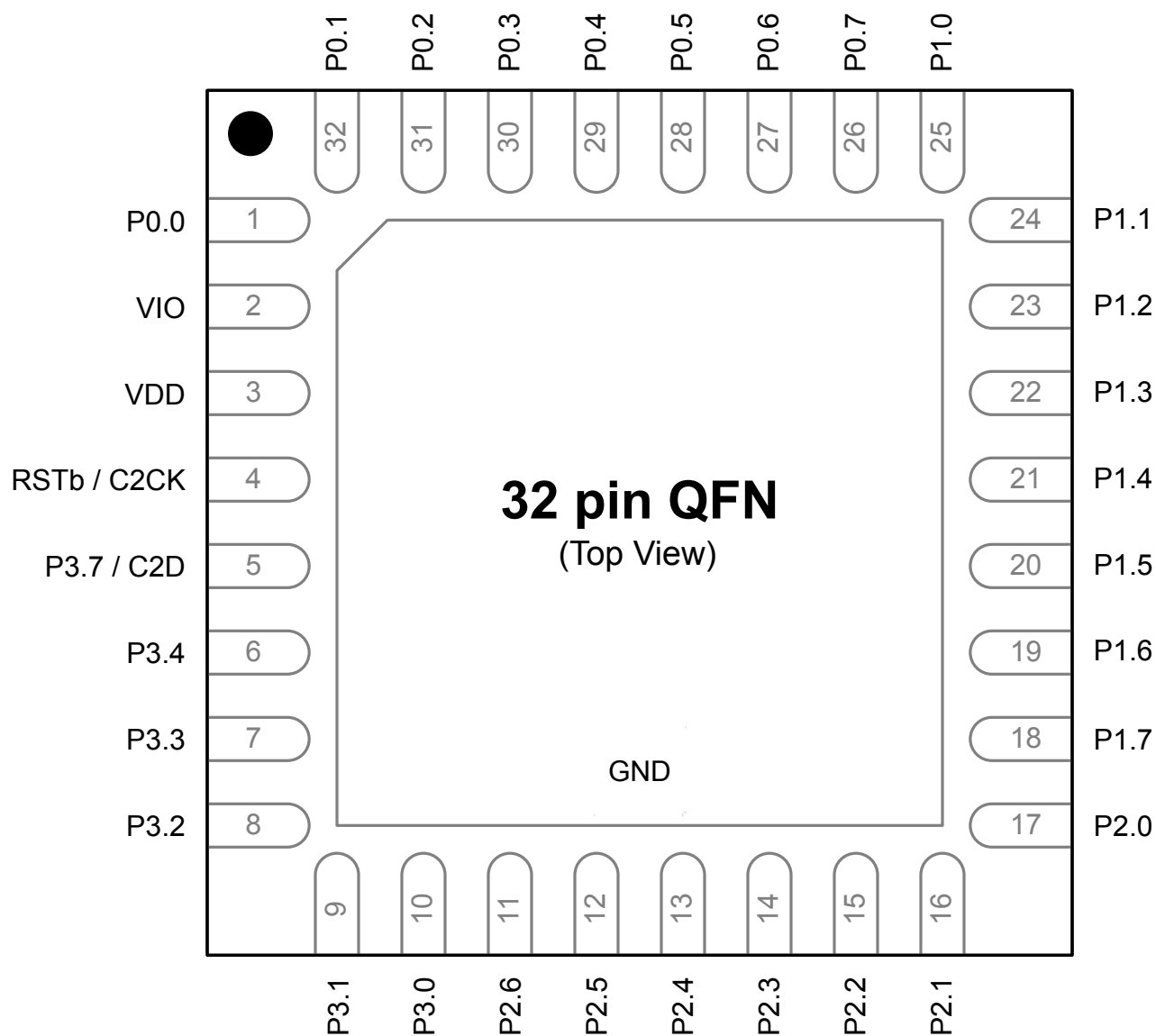


Figure 6.1. EFM8LB1x-QFN32 Pinout

Table 6.1. Pin Definitions for EFM8LB1x-QFN32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
2	VIO	I/O Supply Power Input			
3	VDD	Supply Power Input			
4	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
5	P3.7 / C2D	Multifunction I/O / C2 Debug Data			
6	P3.4	Multifunction I/O			
7	P3.3	Multifunction I/O			DAC3
8	P3.2	Multifunction I/O			DAC2
9	P3.1	Multifunction I/O			DAC1
10	P3.0	Multifunction I/O			DAC0
11	P2.6	Multifunction I/O			ADC0.19 CMP1P.8 CMP1N.8
12	P2.5	Multifunction I/O		CLU3OUT	ADC0.18 CMP1P.7 CMP1N.7
13	P2.4	Multifunction I/O			ADC0.17 CMP1P.6 CMP1N.6
14	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	ADC0.16 CMP1P.5 CMP1N.5

6.2 EFM8LB1x-QFP32 Pin Definitions

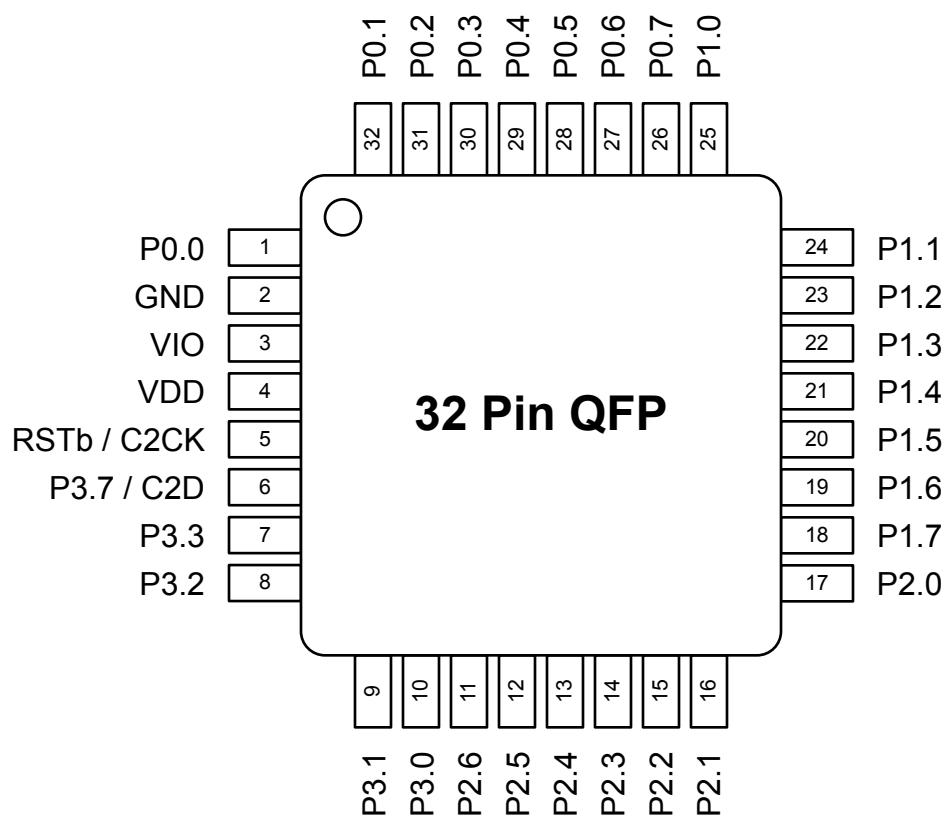


Figure 6.2. EFM8LB1x-QFP32 Pinout

Table 6.2. Pin Definitions for EFM8LB1x-QFP32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
2	GND	Ground			
3	VIO	I/O Supply Power Input			
4	VDD	Supply Power Input			
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			

6.3 EFM8LB1x-QFN24 Pin Definitions

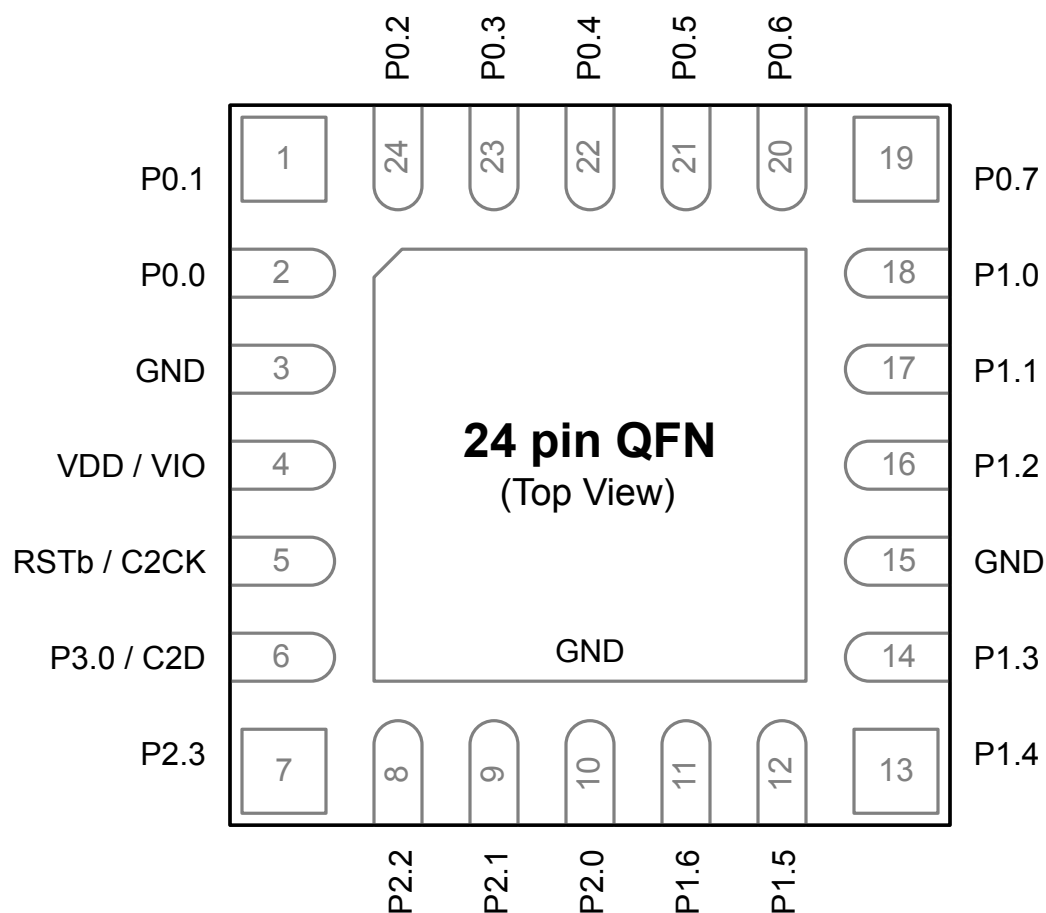


Figure 6.3. EFM8LB1x-QFN24 Pinout

Table 6.3. Pin Definitions for EFM8LB1x-QFN24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
2	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
3	GND	Ground			
4	VDD / VIO	Supply Power Input			
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
6	P3.0 / C2D	Multifunction I/O / C2 Debug Data			
7	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	DAC3
8	P2.2	Multifunction I/O	Yes	P2MAT.2 CLU1A.15 CLU2B.14 CLU3A.14	DAC2
9	P2.1	Multifunction I/O	Yes	P2MAT.1 CLU1B.14 CLU2A.15 CLU3B.15	DAC1
10	P2.0	Multifunction I/O	Yes	P2MAT.0 CLU1A.14 CLU2A.14 CLU3B.14	DAC0
11	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU3OUT CLU0A.15 CLU1B.12 CLU2A.12	ADC0.11 CMP1P.5 CMP1N.5

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
12	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU2OUT CLU0B.14 CLU1A.13 CLU2B.13	ADC0.10 CMP1P.4 CMP1N.4
13	P1.4	Multifunction I/O	Yes	P1MAT.4 I2C0_SCL CLU0A.14 CLU1A.12 CLU2B.12	ADC0.9 CMP1P.3 CMP1N.3
14	P1.3	Multifunction I/O	Yes	P1MAT.3 I2C0_SDA CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	CMP1P.2 CMP1N.2
15	GND	Ground			
16	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12	ADC0.8
17	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.13	ADC0.7
18	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU0A.12 CLU1A.10 CLU2A.10 CLU3B.12	ADC0.6

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
2	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2 CLU0OUT CLU0A.9 CLU2B.8 CLU3A.8	XTAL1 ADC0.1 CMP0P.1 CMP0N.1
3	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND
4	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
5	GND	Ground			
6	VDD / VIO	Supply Power Input			
7	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
8	P3.0 / C2D	Multifunction I/O / C2 Debug Data			
9	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	DAC3
10	P2.2	Multifunction I/O	Yes	P2MAT.2 CLU1A.15 CLU2B.14 CLU3A.14	DAC2

7. QFN32 Package Specifications

7.1 QFN32 Package Dimensions

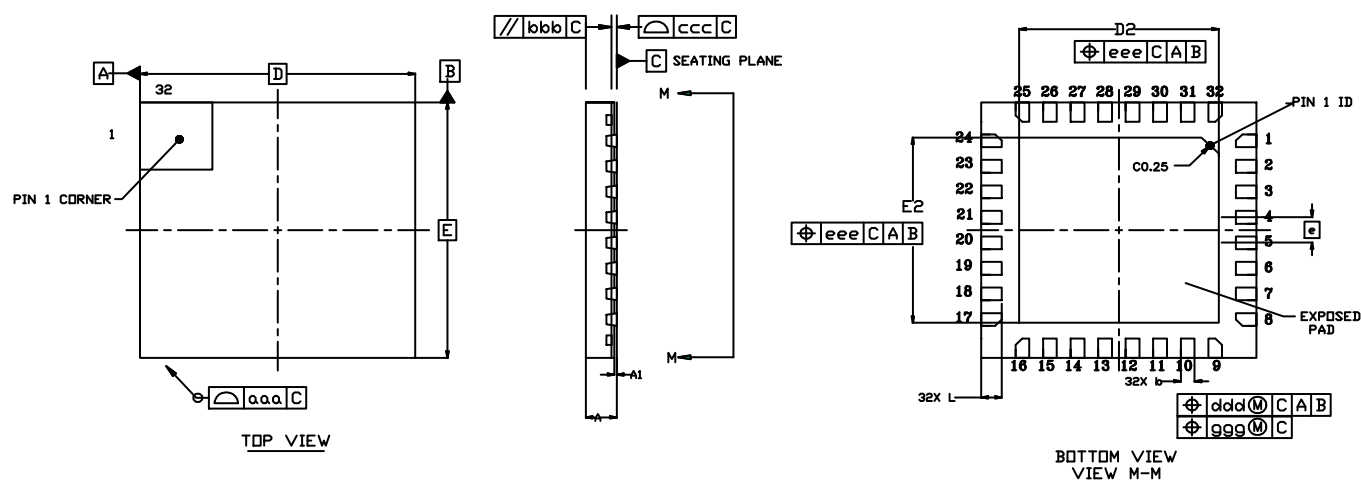


Figure 7.1. QFN32 Package Drawing

Table 7.1. QFN32 Package Dimensions

Dimension	Min	Typ	Max
A	0.45	0.50	0.55
A1	0.00	0.035	0.05
b	0.15	0.20	0.25
D	4.00 BSC.		
D2	2.80	2.90	3.00
e	0.40 BSC.		
E	4.00 BSC.		
E2	2.80	2.90	3.00
L	0.20	0.30	0.40
aaa	—	—	0.10
bbb	—	—	0.10
ccc	—	—	0.08
ddd	—	—	0.10
eee	—	—	0.10
ggg	—	—	0.05

8. QFP32 Package Specifications

8.1 QFP32 Package Dimensions

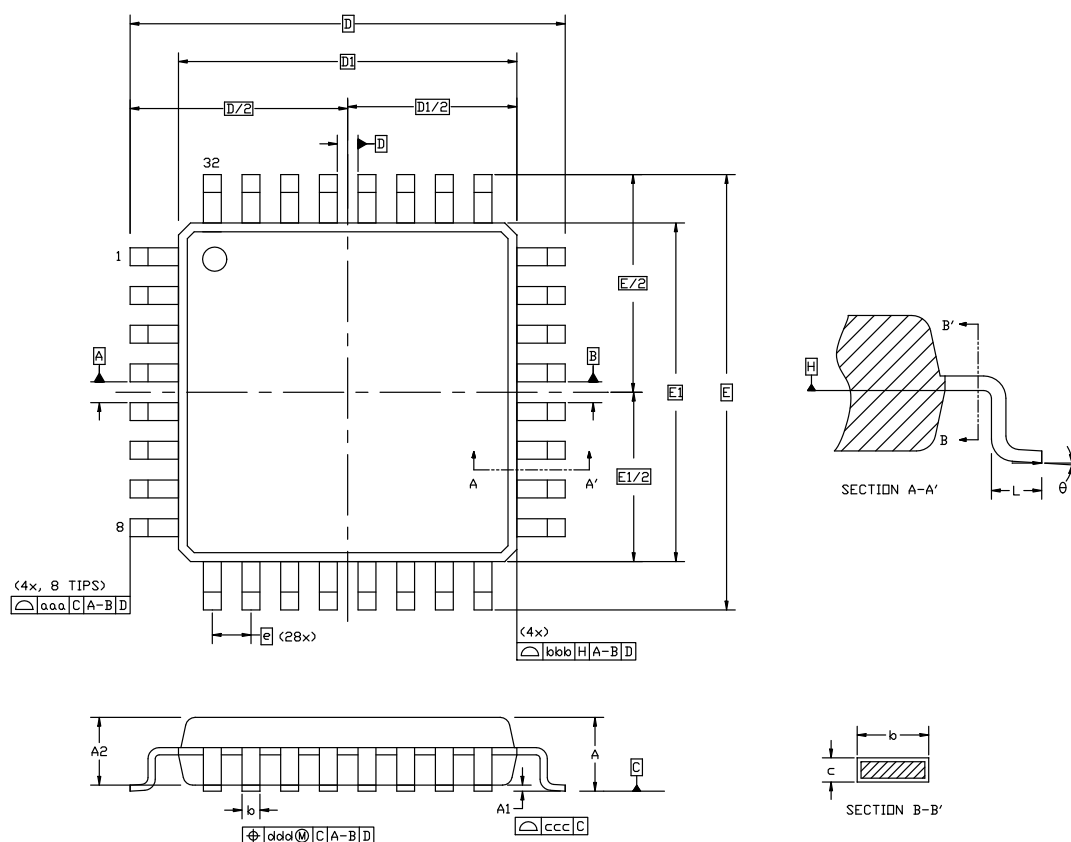


Figure 8.1. QFP32 Package Drawing

Table 8.1. QFP32 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.20
A1	0.05	—	0.15
A2	0.95	1.00	1.05
b	0.30	0.37	0.45
c	0.09	—	0.20
D	9.00 BSC		
D1	7.00 BSC		
e	0.80 BSC		
E	9.00 BSC		
E1	7.00 BSC		
L	0.50	0.60	0.70

8.2 QFP32 PCB Land Pattern

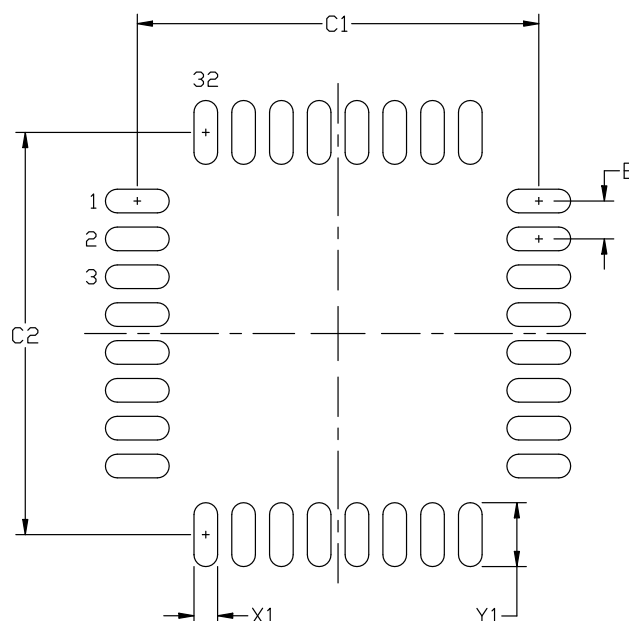


Figure 8.2. QFP32 PCB Land Pattern Drawing

Table 8.2. QFP32 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	8.40	8.50
C2	8.40	8.50
E	0.80 BSC	
X1	0.55	
Y1	1.5	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 μm minimum, all the way around the pad.
4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
5. The stencil thickness should be 0.125 mm (5 mils).
6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
7. A No-Clean, Type-3 solder paste is recommended.
8. The recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

Dimension	Min	Typ	Max
e	0.40 BSC		
e1	0.45 BSC		
J	1.60	1.70	1.80
K	1.60	1.70	1.80
L	0.35	0.40	0.45
L1	0.25	0.30	0.35
aaa	—	0.10	—
bbb	—	0.10	—
ccc	—	0.08	—
ddd	—	0.1	—
eee	—	0.1	—

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-248 but includes custom features which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

10. QSOP24 Package Specifications

10.1 QSOP24 Package Dimensions

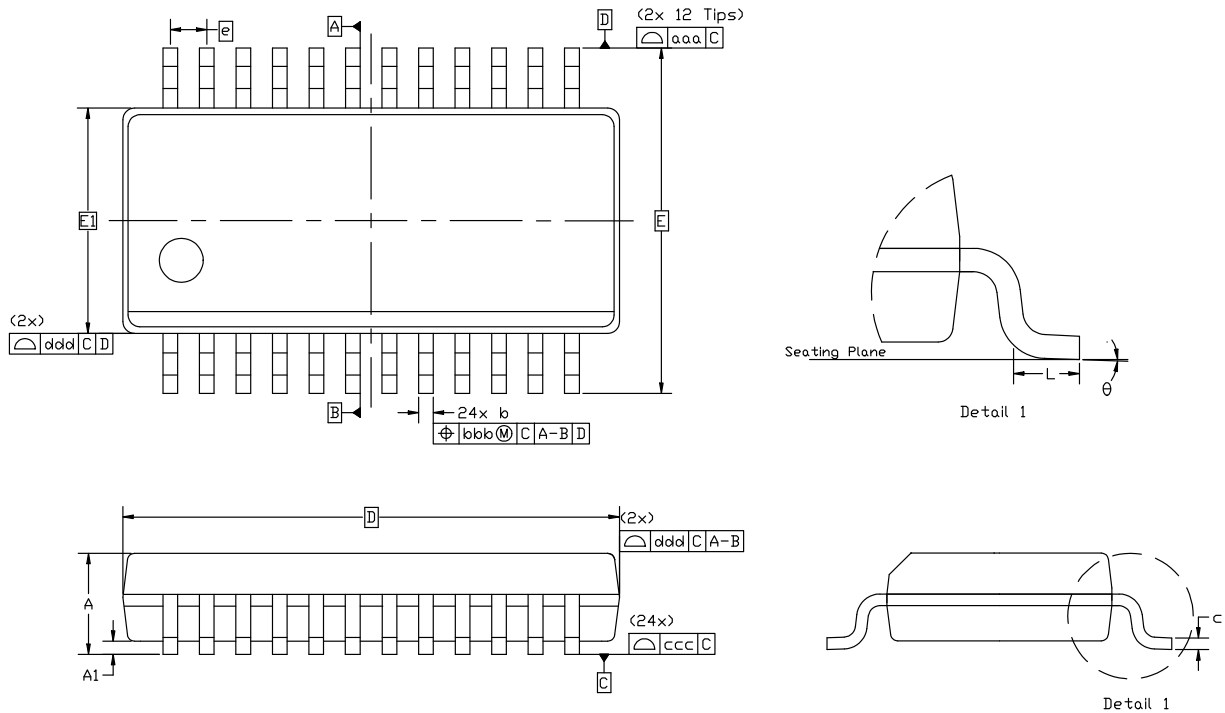


Figure 10.1. QSOP24 Package Drawing

Table 10.1. QSOP24 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.75
A1	0.10	—	0.25
b	0.20	—	0.30
c	0.10	—	0.25
D	8.65 BSC		
E	6.00 BSC		
E1	3.90 BSC		
e	0.635 BSC		
L	0.40	—	1.27
theta	0°	—	8°

10.2 QSOP24 PCB Land Pattern

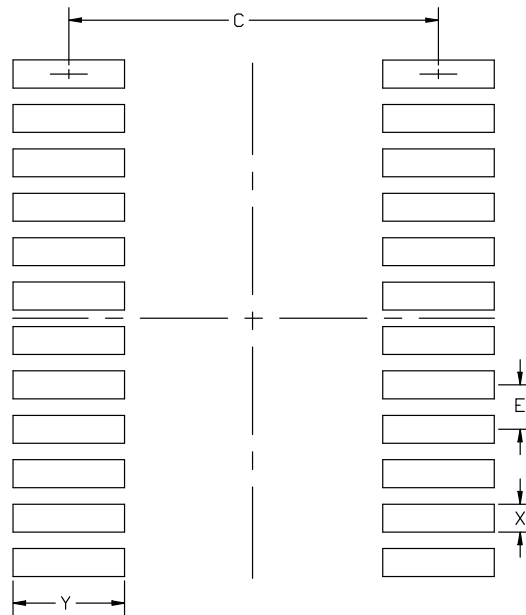


Figure 10.2. QSOP24 PCB Land Pattern Drawing

Table 10.2. QSOP24 PCB Land Pattern Dimensions

Dimension	Min	Max
C	5.20	5.30
E	0.635 BSC	
X	0.30	0.40
Y	1.50	1.60

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This land pattern design is based on the IPC-7351 guidelines.
3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 μ m minimum, all the way around the pad.
4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
5. The stencil thickness should be 0.125 mm (5 mils).
6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
7. A No-Clean, Type-3 solder paste is recommended.
8. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

10.3 QSOP24 Package Marking



Figure 10.3. QSOP24 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).